

Figure 1: Two Polar plots of reciprocal space. The two coordinates of each point on the plot correspond to, an amount of tilt,  $\psi$ , away from the exact (001) planes and also an azimuthal angle,  $\phi$ , that indicates the direction of the tilt. The relative intensities of points on the plot reveal what proportion of the crystal structure is tilted in that direction. Figure (a) corresponds to sample A and Figure (b) corresponds to sample B. The tilt  $\psi$  is measured as the radius and  $\phi$  is the azimuthal angle measured counter-clockwise from the positive x axis. At  $\phi = 0^\circ$  the incident X-ray beam is travelling in the [011] crystallographic direction. Figures (a) and (b) can be thought of as a 2D projection of the surface of the hemisphere shown in (c).

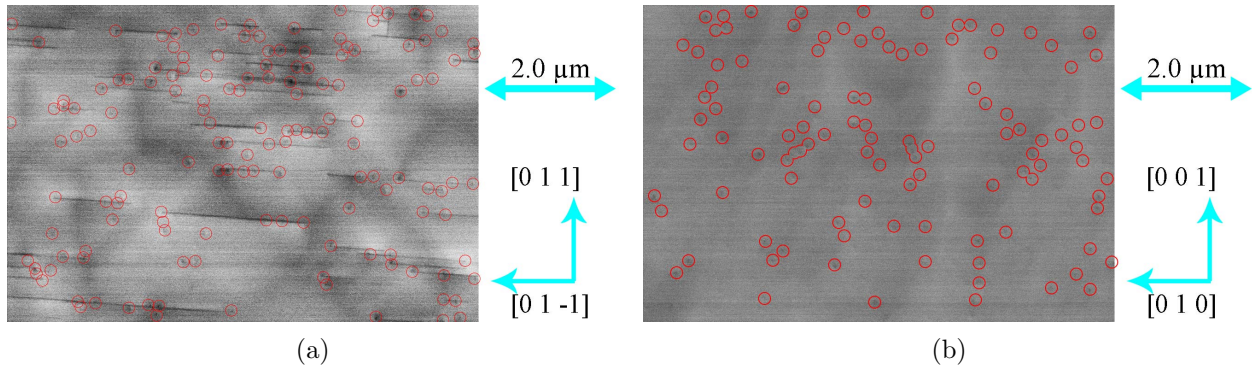


Figure 2: Scanning electron microscope ECCI images for (a) sample A and (b) sample B. Small dots of increased contrast caused by TDD are circled in red. The corresponding crystallographic directions and image scale are indicated by the blue arrows on the right.